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JNL = Journal or Magazine **CNF** = Conference **STD** = Standard**1 Investigation of half-tone phase shift mask with FIB and blue laser repair***Sang-Man Bae; Do-Hwa Lee; Hee-Mok Lee; Myung-Goon Gill; Bong-Ho Kim; L Jun Ahn;*

VLSI and CAD, 1999. ICVC '99. 6th International Conference on , 26-27 Oct. : Pages:159 - 162

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